

10/587941

IAP11 Rec'd PCT/PTO 02 AUG 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of :
Yuji MIYAHARA et al. : **Mail Stop: PCT**
Serial No. NEW : Attorney Docket No. 2006_1275A
Filed August 2, 2006 :

GENE DETECTION FIELD-EFFECT DEVICE
AND METHOD OF ANALYZING GENE
POLYMORPHISM THEREWITH
[Corresponding to PCT/JP2005/001987
Filed February 3, 2005]

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on attached form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

- ☒ each U.S. Patent and U.S. Patent application publication;
- ☐ each reference previously cited in the international application PCT/_____; and/or
- ☐ each reference previously cited in prior parent application Serial No. _____.

1a. ☒ This Information Disclosure Statement is submitted:

within three months of the filing date (or of entry into the National Stage) of the above-entitled application, or

ATTACHMENT C }

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

1b. ☐ This Information Disclosure Statement is submitted

after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

(1) ☐ the certification of paragraph 2 below is provided, **or**

(2) ☐ the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

1c. ☐ This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

the certification of paragraph 2 below is provided, and

the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

2. It is hereby certified

- a. ☐ that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
- b. ☐ that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.

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3. ☐ Consideration of the following list of additional information (including any copending or abandoned U.S. application, prior uses and/or sales, etc.) is requested.
4. For each non-English language reference listed on the attached form PTO-1449, reference is made to:
- a. ☐ a full or partial English language translation submitted herewith,
 - b. ☐ a foreign patent office search report (in the English language) submitted herewith,
 - c. ☐ the concise explanation contained in the specification of the present application at page,
 - d. ☐ the concise explanation set forth in the attached English language abstract,
 - e. ☐ the concise explanation set forth below or on a separate sheet attached to the reference:
5. ☒ A foreign patent office search report citing one or more of the references is enclosed.

Respectfully submitted,

Yuji MIYAHARA et al.

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August 2, 2006

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Sheet 1 of 1		INFORMATION DISCLOSURE STATEMENT		JAP11 Rec'd PCT/PTO 02 AUG 2006			
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: August 2, 2006				ATTY DOCKET NO. 2006_1275A		SERIAL NO. NEW	
				APPLICANT Yuji MIYAHARA et al.			
				FILING DATE August 2, 2006		GROUP	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	2003/0148301	8/2003	Aono et al.			Corresponds to AF
	AB						
	AC						
	AD						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AE	2002-272463	9/2002	JP			Yes
	AF	2001-42498	6/2001	WO			
	AG						
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AH	Y. Miyahara et al., "Potentiometric Detection of DNA Molecules Using Field Effect Transistor", The Japan Society of Applied Physics., No. 3, p. 1180, 30a-S-2, 2003 (English translation enclosed).					
	AI	Y. Miyahara et al., "Biochip Using Micromachining Technology", Journal of Institute of Electrostatics Japan, Vol. 27, No. 6, pp. 268-272, 2003 (English translation enclosed).					
	AJ	T. Sakata et al., Detection of DNA Hybridization by Genetic Transistor", The Japan Society of Applied Physics, No. 3, p. 1179, 30a-S-1, 2003 (English translation enclosed).					
	AK	T. Sakata et al., Potentiometric Detection of DNA Molecules Using Genetic Field Effect Transistor", Denki Gakkai Kenkyukai Shiryo Chemical Sensor Kenkyukai, pp. 1-5, CH5-03-51-55, 2003 (English translation enclosed).					
	AL						
	AM						
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.